



QUAD SITE FT HANDLER MODEL 3160

3160

The Chroma 3160 Handler is a productive pick & place system for high volume multi-site IC testing. Saving floor space, time and cost, the 3160 can increase production productivity and efficiency with its innovative design. The system is configurable for Single, Dual or Quad test sites and can be upgraded to provide an Active Thermal Control (ATC) System to test the DUT up to 150°C.

The Chroma 3160 is also capable of handling various package sizes and types then bins them according to customer specified test results. The system has a reliable handling mechanism, is compatible with standard Conversion Kits and has a streamlined automation sequence, which results in high throughput with low jam rate. Its precisely adjustable contact force, fine alignment positioning and various device sensors also reduces unexpected device damage and helps extend test socket lifetime while maintaining or increasing production yields.

KEY FEATURES

- In Line 1*4 or Matrix 2*2 Flexible DUT Configuration
- 10K pieces Throughput (Dummy Run)
- Programmable Pitch Probes
- Side Mount Capable
- Air Damper Buffer to Reduce Contact Force Impact
- Anti Double Stack & Positioning Protection
- Contact Force Learning
- Color Tray Mode Available
- Yield Monitor (individual contact head)
- Universal Change Kits
- RCAA (Real-time Camera Assist Alignment) for Engineering Adjustment (Patent Pending)



Chroma

SPECIFICATIONS

Model	3160
Dimensions & Weight	Dimensions: 1,700 mm (W) x 1,300 mm (D) x 2,000 mm (H) Weight: Approx. 900 kg
Facility	Power Source: AC220, 50 / 60Hz Single Phase, 10KVA Max. Compressed Air: 0.5MPa or more (dry & clean air), Consumption 120l/min, constant supply
Applicable Device	Package Carried on Type: BGA, QFP, CSP, PLCC, TSOP, PGA...etc. Package Size: 3 mm x 3 mm to 50 mm x 50 mm
Contact Mode	Direct Contact / Drop and Press
Interface	TTL RS232 / GPIB (option)
Multiple Site	4 sites (In line 1 x 4 pitch X =40mm; 2 x 2 Matrix type option)
Contact Area	Test Site: Single, Dual, Quad sites (in-Line) Test Head Area: 550 mm (from socket center), Height: 1,000 mm (900/1, 100mm option)
Index Time	0.38 sec (tester communication time excluded)
Jam Rate	1/10000
Applicable Tray	JEDEC 135.9mm (W) x 315 mm (L) Applicable tray thickness: 7.62mm, 12.2mm
Category	6 categories (3 auto, 3 manual)
Binning	16 bin signal for TTL
Contact Force	50 kgf (accuracy \pm 1 kgf) 80 kgf (option)
Temperature	Operating Mode: Ambient
High Temperature (Option)	Operating Mode: 40°C ~ 150°C (heating time: within 30 min.) Accuracy : Contact Head \pm 3 °C, Pre-heater \pm 5 °C

All specifications are subject to change without notice.



Loading



In-line Test Site



Unloading

Developed and Manufactured by :

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